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(71) Applicant(s):

KONINKLIJKE PHILIPS ELECTRONICS N.V. [NL/NL]; Groenewoudseweg 1 NL-5621 BA Eindhoven (NL) *(for all designated states except US)*

SCHUURMANS, Frank, J., P. [NL/NL]; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL) *(for US only)*

VAN BEEK, Michael, C. [NL/NL]; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL) *(for US only)*

BAKKER, Levinus, P. [NL/NL]; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL) *(for US only)*

RENSEN, Wouter, H., J. [NL/NL]; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL) *(for US only)*

HENDRIKS, Bernardus, H., W. [NL/NL]; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL) *(for US only)*

HENDRIKS, Robert, F., M. [NL/NL]; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL) *(for US only)*

STEFFEN, Thomas [DE/NL]; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL) *(for US only)*

(72) Inventor(s):

SCHUURMANS, Frank, J., P.; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL)

VAN BEEK, Michael, C.; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL)

BAKKER, Levinus, P.; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL)

RENSEN, Wouter, H., J.; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL)

HENDRIKS, Bernardus, H., W.; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL)

HENDRIKS, Robert, F., M.; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL)

STEFFEN, Thomas; c/o Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL)

(74) Agent(s):

SCHOUTEN, Marcus, M.; Philips Intellectual Property & Standards Prof. Holstlaan 6 NL-5656 AA Eindhoven (NL)

(54) Title (EN): OPTICAL ANALYSIS SYSTEM

(54) Title (FR): SYSTEME D'ANALYSE OPTIQUE

(57) Abstract:

(EN): The optical analysis system (20) for determining an amplitude of a principal component of an optical signal comprises a multivariate optical element (10) for reflecting the optical signal and thereby weighing the optical signal by a spectral weighing function, and a detector (9, 9P, 9N) for detecting the weighed optical signal. The optical analysis system (20) may further comprise a dispersive element (2) for spectrally dispersing the optical signal, the multivariate optical element being arranged to receive the dispersed optical signal. The blood analysis system (40) comprises the optical analysis system (20) according to the invention.

(FR): Cette invention concerne un système d'analyse optique (20) permettant de déterminer l'amplitude d'une première composante d'un signal optique, qui comprend un élément optique multivariable (10) reflétant le signal optique et par la même pondérant ledit signal au moyen d'une fonction de pondération spectrale, et un détecteur (9, 9P, 9N) détectant le signal optique pondéré. Le système d'analyse optique (20) peut comporter en outre un élément de dispersion (2) assurant une dispersion spectrale

du signal optique, l'élément optique multivariables étant conçu de manière à recevoir le signal optique dispersé. Le système d'analyse de sang (40) comprend le système d'analyse optique (20) de l'invention.

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Declarations:

Declaration made as applicant's entitlement, as at the international filing date, to apply for and be granted a patent (Rules 4.17(ii) and 51bis.1(a)(ii)), in a case where the declaration under Rule 4.17(iv) is not appropriate